


<b>Search Notes</b>  	<b>Application/Control No.</b>  10550824	<b>Applicant(s)/Patent Under Reexamination</b>  HIRANO ET AL.
	<b>Examiner</b>  Nguyen, Khiem D	<b>Art Unit</b>  2823

SEARCHED			
Class	Subclass	Date	Examiner
438	48, 70	6/10/2007	K.N.
257	294, 431, 444, E31.121, E31.122, E31.123, E33.076	6/10/2007	K.N.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	6/10/2007	K.N.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner